

2N4402



PNP General Purpose Amplifier

This device is designed for use as general purpose amplifiers and switches requiring collector currents to 500 mA.

Absolute Maximum Ratings*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
V_{CEO}	Collector-Emitter Voltage	40	V
V _{CBO}	Collector-Base Voltage	40	V
V _{EBO}	Emitter-Base Voltage	5.0	V
Ic	Collector Current - Continuous	600	mA
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

1) These ratings are based on a maximum junction temperature of 150 degrees C.

2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics TA = 25°C unless otherwise noted

Symbol	Characteristic	Max	Units
		2N4402	
P _D	Total Device Dissipation Derate above 25°C	625 5.0	mW mW/°C
R _{θJC}	Thermal Resistance, Junction to Case	83.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	200	°C/W

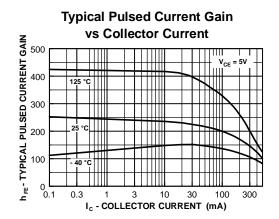
PNP General Purpose Amplifier (continued)

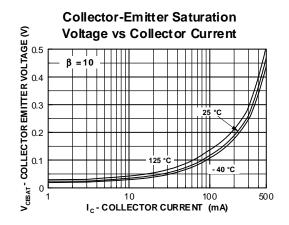
Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	RACTERISTICS				
$V_{(BR)CEO}$	Collector-Emitter Breakdown Voltage*	$I_C = 1.0 \text{ mA}, I_B = 0$	40		V
V _{(BR)CBO}	Collector-Base Breakdown Voltage	$I_C = 100 \mu\text{A}, I_E = 0$	40		V
V _{(BR)EBO}	Emitter-Base Breakdown Voltage	$I_E = 100 \mu A, I_C = 0$	5.0		V
I _{CEX}	Collector Cutoff Current	$V_{CE} = 35 \text{ V}, V_{EB} = 0.4 \text{ V}$		0.1	μΑ
I _{BL}	Base Cutoff Current	$V_{CE} = 35 \text{ V}, V_{EB} = 0.4 \text{ V}$		0.1	μΑ
ON CHAF	RACTERISTICS*				
h _{FE}	DC Current Gain	$V_{CE} = 1.0 \text{ V}, I_{C} = 1.0 \text{ mA}$	30		
		$V_{CE} = 1.0 \text{ V}, I_{C} = 10 \text{ mA}$	50	450	
		$V_{CE} = 2.0 \text{ V}, I_{C} = 150 \text{ mA}$ $V_{CE} = 2.0 \text{ V}, I_{C} = 500 \text{ mA}$	50 20	150	
V _{CE(sat)}	Collector-Emitter Saturation Voltage	$I_C = 150 \text{ mA}, I_B = 15 \text{ mA}$		0.40	V
		$I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$		0.75	V
$V_{BE(sat)}$	Base-Emitter Saturation Voltage	$I_C = 150 \text{ mA}, I_B = 15 \text{ mA}$ $I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$	0.75	0.95 1.30	V
		1C = 300 111/1, 1B = 30 111/1		1.00	
CMALLC	IGNAL CHARACTERISTICS				
C _{ob}		V _{CB} = 10 V, f = 140 kHz			
				8.5	nF
	Output Capacitance			8.5	pF
C _{ib}	Input Capacitance	V _{EB} = 0.5 V, f = 140 kHz	1.5	8.5 30	pF pF
C _{ib}	· · ·	$V_{EB} = 0.5 \text{ V}, f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA}, V_{CE} = 10 \text{ V},$	1.5		
C _{ib}	Input Capacitance	V _{EB} = 0.5 V, f = 140 kHz	1.5		
C _{ib} h _{fe}	Input Capacitance Small-Signal Current Gain	$V_{EB} = 0.5 \text{ V}, f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA}, V_{CE} = 10 \text{ V},$ $f = 100 \text{ MHz}$		30	<u> </u>
C _{ib} h _{fe} h _{fe}	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$	30	30	pF kΩ
C _{ib} h _{fe} h _{fe} h _{ie} h _{re}	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$	30 0.75	30 250 7.5	pF
Cib hfe hfe hie hre hoe	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$	30 0.75 0.10	30 250 7.5 8.0	pF kΩ x10 ⁻⁴
C _{ib} h _{fe} h _{fe} h _{ie} h _{re} h _{oe}	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio Output Admittance	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$	30 0.75 0.10	30 250 7.5 8.0	pF kΩ x10 ⁻⁴
C _{ib} h _{fe} h _{fe} h _{ie} h _{re} h _{oe}	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio Output Admittance NG CHARACTERISTICS	$V_{EB} = 0.5 \text{ V}, f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA}, V_{CE} = 10 \text{ V},$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA}, V_{CE} = 10 \text{ V},$ $f = 1.0 \text{ kHz}$	30 0.75 0.10	250 7.5 8.0 100	pF kΩ x10 ⁻⁴ μmhos
C _{ib} h _{fe} h _{fe} h _{ie} h _{re} h _{oe} SWITCHI	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio Output Admittance NG CHARACTERISTICS Delay Time	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 1.0 \text{ kHz}$ $V_{CC} = 30 \text{ V, } I_{C} = 150 \text{ mA,}$	30 0.75 0.10	30 250 7.5 8.0 100	pF kΩ x10 ⁻⁴ μmhos
C _{ib} h _{fe} h _{fe} h _{ie} h _{re} h _{oe} SWITCHI t _d	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio Output Admittance NG CHARACTERISTICS Delay Time Rise Time	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V, }$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V, }$ $f = 1.0 \text{ kHz}$ $V_{CC} = 30 \text{ V, } I_{C} = 150 \text{ mA, }$ $I_{B1} = 15 \text{ mA, } V_{BE \text{ (off)}} = 2.0 \text{ V}$	30 0.75 0.10	30 250 7.5 8.0 100 15 20	pF kΩ x10 ⁻⁴ μmhos ns
C _{ib} h _{fe} h _{fe} h _{ie} h _{re} h _{oe}	Input Capacitance Small-Signal Current Gain Small-Signal Current Gain Input Impedance Voltage Feedback Ratio Output Admittance NG CHARACTERISTICS Delay Time	$V_{EB} = 0.5 \text{ V, } f = 140 \text{ kHz}$ $I_{C} = 20 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 100 \text{ MHz}$ $I_{C} = 1.0 \text{ mA, } V_{CE} = 10 \text{ V,}$ $f = 1.0 \text{ kHz}$ $V_{CC} = 30 \text{ V, } I_{C} = 150 \text{ mA,}$	30 0.75 0.10	30 250 7.5 8.0 100	pF kΩ x10 ⁻⁴ μmhos

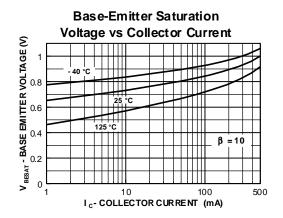
^{*}Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

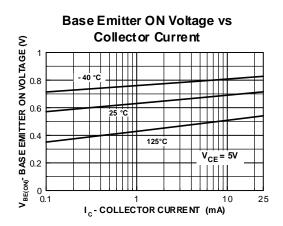
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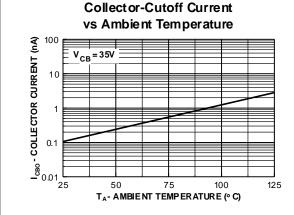
Typical Characteristics

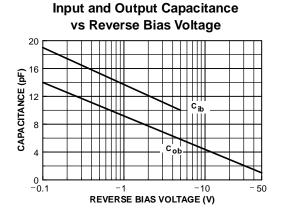






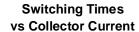


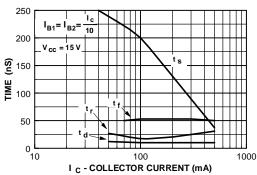




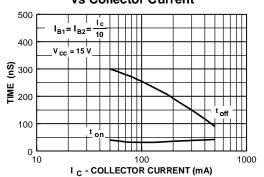
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Typical Characteristics (continued)

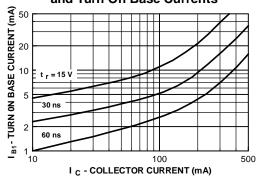




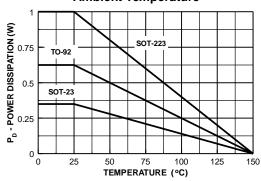
Turn On and Turn Off Times vs Collector Current



Rise Time vs Collector and Turn On Base Currents

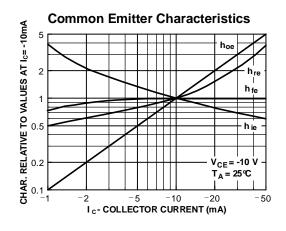


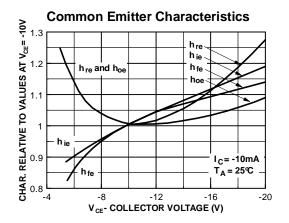
Power Dissipation vs Ambient Temperature

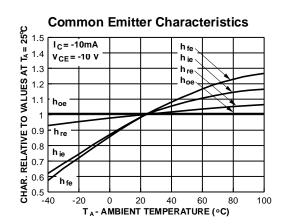


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Typical Common Emitter Characteristics (f = 1.0kHz)







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Test Circuits

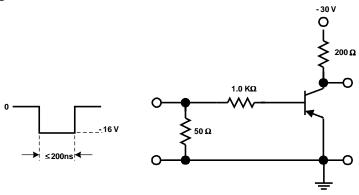


FIGURE 1: Saturated Turn-On Switching Time Test Circuit

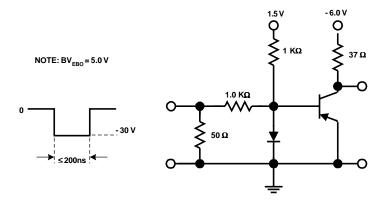


FIGURE 2: Saturated Turn-Off Switching Time Test Circuit

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